Abstract

The thermal annealing behavior of the SnO2 thin films elaborated by sol–gel method has been studied by the neutrons reflectivity technique. From the fit of the experimental data using Parratt32 software program developed at HMI, Berlin, scattering length density, thickness and roughness are extracted. The obtained results show that the film thickness increases with the increasing annealing temperature, and the roughness is higher at 500 7deg;C. Whereas, approximately, the same scattering length density is obtained after each annealing temperature